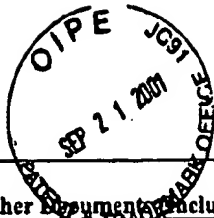




Form PTO 1449 (Rev. 2-32)		U.S. Department of Commerce Patent and Trademark Office		Atty. Docket No. CAY-006		Serial No. 09/943,338		
Information Disclosure Statement by Applicant				Applicant: John M. Caywood				
(Use several sheets if necessary)				Filed: 8/28/2001 Group: (to be assigned) 2819				
U.S. Patent Documents								
Init.		Document No.	Date	Name	Class	Subclass	Filing Date	
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B		4,035,820	7/12/77	Matzen	357	23	12/29/75	
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Examiner	Date Considered 9/31/04
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include a copy of this form with the next communication to applicant.	